# 2.5V/3.3V SiGe Differential 1:4 Clock/Data Driver with RSECL\* Outputs

## \*Reduced Swing ECL

#### Description

The NBSG14 is a 1-to-4 clock/data distribution chip, optimized for ultra-low skew and jitter.

Inputs incorporate internal 50  $\Omega$  termination resistors and accept NECL (Negative ECL), PECL (Positive ECL), LVTTL, LVCMOS, CML, or LVDS. Outputs are RSECL (Reduced Swing ECL), 400 mV.

#### **Features**

- Maximum Input Clock Frequency up to 12 GHz Typical
- Maximum Input Data Rate up to 12 Gb/s Typical
- 30 ps Typical Rise and Fall Times
- 125 ps Typical Propagation Delay
- RSPECL Output with Operating Range:  $V_{CC}$  = 2.375 V to 3.465 V with  $V_{EE}$  = 0 V
- RSNECL Output with RSNECL or NECL Inputs with Operating Range: V<sub>CC</sub> = 0 V with V<sub>EE</sub> = −2.375 V to −3.465 V
- RSECL Output Level (400 mV Peak-to-Peak Output), Differential Output
- 50  $\Omega$  Internal Input Termination Resistors
- Compatible with Existing 2.5 V/3.3 V LVEP, EP, and LVEL Devices
- Pb-Free Packages are Available



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#### **MARKING DIAGRAMS\***



FCBGA-16 BA SUFFIX CASE 489





QFN-16 MN SUFFIX CASE 485G

1



A = Assembly Location

= Wafer Lot

Y = Year

W = Work Week

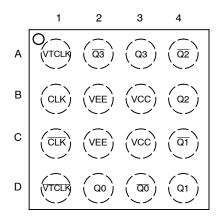
= Pb-Free Package

(Note: Microdot may be in either location)

\*For additional marking information, refer to Application Note AND8002/D.

#### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 11 of this data sheet.



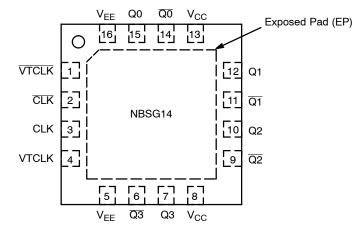


Figure 1. BGA-16 Pinout (Top View)

Figure 2. QFN-16 Pinout (Top View)

**Table 1. Pin Description** 

Р	in			
BGA	QFN	Name	I/O	Description
D1	1	VTCLK	-	Internal 50 $\Omega$ Termination pin. See Table 2.
C1	2	CLK	ECL, CML, LVCMOS, LVDS, LVTTL Input	Inverted Differential Input. Internal 75 k $\Omega$ to V <sub>EE</sub> and 36.5 k $\Omega$ to V <sub>CC</sub> .
B1	3	CLK	ECL, CML, LVCMOS, LVDS, LVTTL Input	Noninverted Differential Input. Internal 75 k $\Omega$ to VEE.
A1	4	VTCLK	=	Internal 50 $\Omega$ Termination Pin. See Table 2.
B2,C2	5,16	V <sub>EE</sub>	-	Negative Supply Voltage. All $V_{\text{EE}}$ Pins must be Externally Connected to Power Supply to Guarantee Proper Operation.
A2*	6	Q3	RSECL Output	Inverted Differential Output 3. Typically Terminated with 50 $\Omega$ to V <sub>TT</sub> = V <sub>CC</sub> – 2 V*
A3*	7	Q3	RSECL Output	Noninverted Differential Output 3. Typically Terminated with 50 $\Omega$ to $V_{TT}$ = $V_{CC}$ – 2 V*
B3,C3	8,13	V <sub>CC</sub>	-	Positive Supply Voltage. All $V_{CC}$ Pins must be Externally Connected to Power Supply to Guarantee Proper Operation.
A4*	9	Q2	RSECL Output	Inverted Differential Output 2. Typically Terminated with 50 $\Omega$ to V <sub>TT</sub> = V <sub>CC</sub> – 2 V*
B4*	10	Q2	RSECL Output	Noninverted Differential Output 2. Typically Terminated with 50 $\Omega$ to $V_{TT}$ = $V_{CC}$ – 2 V*
C4*	11	Q1	RSECL Output	Inverted Differential Output 1. Typically Terminated with 50 $\Omega$ to V <sub>TT</sub> = V <sub>CC</sub> – 2 V*
D4*	12	Q1	RSECL Output	Noninverted Differential Output 1. Typically Terminated with 50 $\Omega$ to $V_{TT}$ = $V_{CC}$ – 2 V*
D3*	14	Q0	RSECL Output	Inverted Differential Output 0. Typically Terminated with 50 $\Omega$ to V <sub>TT</sub> = V <sub>CC</sub> – 2 V*
D2*	15	Q0	RSECL Output	Noninverted Differential Output 0. Typically Terminated with 50 $\Omega$ to $V_{TT}$ = $V_{CC}$ – 2 $V^*$
N/A	_	EP	-	Exposed Pad. The thermally exposed pad on package bottom (see case drawing) must be attached to a heat-sinking conduit.

<sup>1.</sup> In the differential configuration when the input termination pins (VTCLK, VTCLK) are connected to a common termination voltage, if no signal is applied then the device will be susceptible to self-oscillation. \*Devices in BGA package typically terminated with 50  $\Omega$  to V<sub>TT</sub> = V<sub>CC</sub> - 1.5 V.

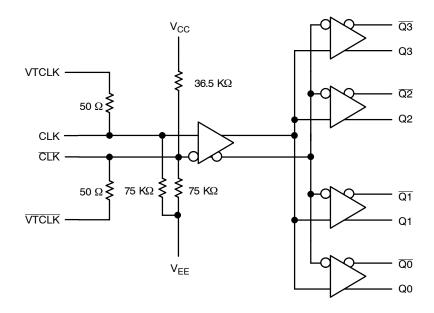


Figure 3. Logic Diagram

**Table 2. INTERFACING OPTIONS** 

INTERFACING OPTIONS	CONNECTIONS
CML	Connect VTCLK and VTCLK to VCC
LVDS	Connect VTCLK and VTCLK Together
AC-COUPLED	Bias VTCLK and VTCLK Inputs within Common Mode Range (V <sub>IHCMR</sub> )
RSECL, PECL, NECL	Standard ECL Termination Techniques
LVTTL, LVCMOS	An External Voltage ( $V_{THR}$ ) should be Applied to the Unused Differential Input. Nominal $V_{THR}$ is 1.5 V for LVTTL and $V_{CC}/2$ for LVCMOS Inputs. This Voltage must be within the $V_{THR}$ Specification.

Table 3. ATTRIBUTES

Characterist	ics	Value	Value			
Internal Input Pulldown Resistor (Cl	75 kΩ					
Internal Input Pullup Resistor (CLK)	36.5	i kΩ				
ESD Protection	> 2 kV > 100 V					
Moisture Sensitivity (Note 1)	Pb Pkg	Pb-Free Pkg				
	FCBGA-16 QFN-16	Level 3 Level 1	N/A Level 1			
Flammability Rating	Oxygen Index: 28 to 34	UL 94 V-0 @ 0.125 in				
Transistor Count	158					
Meets or exceeds JEDEC Spec EIA/JESD78 IC Latchup Test						

<sup>1.</sup> For additional information, see Application Note AND  $\overline{8003/D}$ .

**Table 4. MAXIMUM RATINGS** 

Symbol	Parameter	Condition 1	Condition 2	Rating	Unit
V <sub>CC</sub>	Positive Power Supply	V <sub>EE</sub> = 0 V		3.6	V
V <sub>EE</sub>	Negative Power Supply	V <sub>CC</sub> = 0 V		-3.6	V
VI	Positive Input Negative Input	V <sub>EE</sub> = 0 V V <sub>CC</sub> = 0 V	$V_{I} \leq V_{CC}$ $V_{I} \geq V_{EE}$	3.6 -3.6	V
V <sub>INPP</sub>	Differential Input Voltage  CLK-CLK	$\begin{array}{c} V_{CC} - V_{EE} \geq 2.8 \ V \\ V_{CC} - V_{EE} < 2.8 \ V \end{array}$		2.8  V <sub>CC</sub> -V <sub>EE</sub>	V
I <sub>IN</sub>	Input Current Through $R_T$ (50 $\Omega$ Resistor)	Static Surge		45 80	mA mA
l <sub>OUT</sub>	Output Current	Continuous Surge		25 50	mA mA
T <sub>A</sub>	Operating Temperature Range	16 FCBGA 16 QFN		-40 to +70 -40 to +85	°C
T <sub>stg</sub>	Storage Temperature Range			-65 to +150	°C
θ <sub>JA</sub>	Thermal Resistance (Junction-to-Ambient) (Note 2)	0 Ifpm 500 Ifpm 0 Ifpm 500 Ifpm	16 FCBGA 16 FCBGA 16 QFN 16 QFN	108 86 41.6 35.2	°C/W °C/W °C/W
$\theta_{\text{JC}}$	Thermal Resistance (Junction-to-Case)	2S2P (Note 2) 2S2P (Note 3)	16 FCBGA 16 QFN	5 4.0	°C/W
T <sub>sol</sub>	Wave Solder Pb Pb-Free			225 225	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

2. JEDEC standard 51–6, multilayer board – 2S2P (2 signal, 2 power).

3. JEDEC standard multilayer board – 2S2P (2 signal, 2 power) with 8 filled thermal vias under exposed pad.

Table 5. DC CHARACTERISTICS, INPUT WITH RSPECL OUTPUT V<sub>CC</sub> = 2.5 V; V<sub>EE</sub> = 0 V (Note 4)

			-40°C			25°C		70°C(B	(QFN)**		
Symbol	Characteristic	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
I <sub>EE</sub>	Negative Power Supply Current	45	60	75	45	60	75	45	60	75	mA
V <sub>OH</sub>	Output HIGH Voltage (Note 5)	1525	1575	1625	1550	1610	1650	1575	1635	1675	mV
V <sub>OUTPP</sub>	Output Amplitude Voltage	315	405	495	315	405	495	315	405	495	mV
V <sub>IH</sub>	Input HIGH Voltage (Single-Ended) (Notes 7 and 9)	V <sub>CC</sub> - 1435	V <sub>CC</sub> - 1000*	V <sub>CC</sub>	V <sub>CC</sub> - 1435	V <sub>CC</sub> - 1000*	V <sub>CC</sub>	V <sub>CC</sub> - 1435	V <sub>CC</sub> - 1000*	V <sub>CC</sub>	mV
V <sub>IL</sub>	Input LOW Voltage (Single-Ended) (Notes 8 and 9)	V <sub>IH</sub> - 2500	V <sub>CC</sub> - 1400*	V <sub>IH</sub> - 150	V <sub>IH</sub> - 2500	V <sub>CC</sub> - 1400*	V <sub>IH</sub> - 150	V <sub>IH</sub> - 2500	V <sub>CC</sub> - 1400*	V <sub>IH</sub> - 150	mV
V <sub>THR</sub>	Input Threshold Voltage (Single-Ended) (Note 9)	V <sub>EE</sub> + 1125		V <sub>CC</sub> - 75	V <sub>EE</sub> + 1125		V <sub>CC</sub> - 75	V <sub>EE</sub> + 1125		V <sub>CC</sub> - 75	mV
V <sub>IHCMR</sub>	Input HIGH Voltage Common Mode Range (Differential Configuration) (Note 6)	1.2		2.5	1.2		2.5	1.2		2.5	V
R <sub>TIN</sub>	Internal Input Termination Resistor	45	50	55	45	50	55	45	50	55	Ω
I <sub>IH</sub>	Input HIGH Current (@ V <sub>IH</sub> )		80	150		80	150		80	150	μΑ
I <sub>IL</sub>	Input LOW Current (@ V <sub>IL</sub> )		25	100		25	100		25	100	μΑ

- 4. Input and output parameters vary 1:1 with V<sub>CC</sub>. V<sub>EE</sub> can vary +0.125 V to -0.5 V.
  5. All outputs loaded with 50  $\Omega$  to V<sub>CC</sub> 1.5 V for BGA package and V<sub>CC</sub> 2 V for QFN package. V<sub>OH</sub>/V<sub>OL</sub> measured at V<sub>IH</sub>/V<sub>IL</sub> (Typical).
- 6. VIHCMR min varies 1:1 with VEE, VIHCMR max varies 1:1 with VCC. The VIHCMR range is referenced to the most positive side of the differential input signal.

- 7. V<sub>IH</sub> cannot exceed V<sub>CC</sub>. |V<sub>IH</sub> V<sub>THR</sub>| < 2600 mV.</li>
  8. V<sub>IL</sub> always ≥ V<sub>EE</sub>. |V<sub>IL</sub> V<sub>THR</sub>| < 2600 mV.</li>
  9. V<sub>THR</sub> is the voltage applied to one input when running in single–ended mode.

<sup>\*</sup>Typicals used for testing purposes.

<sup>\*\*</sup>The device packaged in FCBGA-16 have maximum temperature specification of 70°C and devices packaged in QFN-16 have maximum temperature specification of 85°C.

Table 6. DC CHARACTERISTICS, INPUT WITH RSPECL OUTPUT  $V_{CC} = 3.3 \text{ V}$ ;  $V_{EE} = 0 \text{ V}$  (Note 10)

			-40°C			25°C		70°C(B	(QFN)**		
Symbol	Characteristic	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
I <sub>EE</sub>	Negative Power Supply Current	45	60	75	45	60	75	45	60	75	mA
V <sub>OH</sub>	Output HIGH Voltage (Note 11)	2325	2375	2425	2350	2410	2450	2375	2435	2475	mV
V <sub>OUTPP</sub>	Output Amplitude Voltage	350	440	530	350	440	530	350	440	530	mV
V <sub>IH</sub>	Input HIGH Voltage (Single-Ended) (Notes 13 and 15)	V <sub>CC</sub> - 1435	V <sub>CC</sub> - 1000*	V <sub>CC</sub>	V <sub>CC</sub> - 1435	V <sub>CC</sub> - 1000*	V <sub>CC</sub>	V <sub>CC</sub> - 1435	V <sub>CC</sub> - 1000*	V <sub>CC</sub>	mV
V <sub>IL</sub>	Input LOW Voltage (Single-Ended) (Notes 14 and 15)	V <sub>IH</sub> - 2500	V <sub>CC</sub> - 1400*	V <sub>IH</sub> - 150	V <sub>IH</sub> - 2500	V <sub>CC</sub> - 1400*	V <sub>IH</sub> - 150	V <sub>IH</sub> - 2500	V <sub>CC</sub> - 1400*	V <sub>IH</sub> - 150	mV
$V_{THR}$	Input Threshold Voltage (Single-Ended) (Note 15)	V <sub>EE</sub> + 1125		V <sub>CC</sub> - 75	V <sub>EE</sub> + 1125		V <sub>CC</sub> - 75	V <sub>EE</sub> + 1125		V <sub>CC</sub> - 75	mV
V <sub>IHCMR</sub>	Input HIGH Voltage Common Mode Range (Differential Configuration) (Note 12)	1.2		3.3	1.2		3.3	1.2		3.3	٧
R <sub>TIN</sub>	Internal Input Termination Resistor	45	50	55	45	50	55	45	50	55	Ω
I <sub>IH</sub>	Input HIGH Current (@ V <sub>IH</sub> )		80	150		80	150		80	150	μΑ
I <sub>IL</sub>	Input LOW Current (@ V <sub>IL</sub> )		25	100		25	100		25	100	μΑ

<sup>\*</sup>Typicals used for testing purposes.

<sup>\*\*</sup>The device packaged in FCBGA-16 have maximum temperature specification of 70°C and devices packaged in QFN-16 have maximum temperature specification of 85°C.

<sup>10.</sup> Input and output parameters vary 1:1 with V<sub>CC</sub>. V<sub>EE</sub> can vary +0.3 V to -0.165 V. 11. All outputs loaded with 50  $\Omega$  to V<sub>CC</sub> - 1.5 V for BGA package and V<sub>CC</sub> - 2 V for QFN package. V<sub>OH</sub>/V<sub>OL</sub> measured at V<sub>IH</sub>/V<sub>IL</sub> (Typical).

<sup>12.</sup> V<sub>IHCMR</sub> min varies 1:1 with V<sub>EE</sub>, V<sub>IHCMR</sub> max varies 1:1 with V<sub>CC</sub>. The V<sub>IHCMR</sub> range is referenced to the most positive side of the differential input signal.

<sup>13.</sup> V<sub>IH</sub> cannot exceed V<sub>CC</sub>.  $|V_{IH} - V_{THR}| < 2600$  mV. 14. V<sub>IL</sub> always  $\geq V_{EE}$ .  $|V_{IL} - V_{THR}| < 2600$  mV. 15. V<sub>THR</sub> is the voltage applied to one input when running in single–ended mode.

#### Table 7. DC CHARACTERISTICS, NECL OR RSNECL INPUT WITH NECL OUTPUT

 $V_{CC} = 0 \text{ V}; V_{EE} = -3.465 \text{ V to } -2.375 \text{ V (Note 16)}$ 

			-40°C			25°C		70°C(B	GA)/85°C	(QFN)**	
Symbol	Characteristic	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
I <sub>EE</sub>	Negative Power Supply Current	45	60	75	45	60	75	45	60	75	mA
V <sub>OH</sub>	Output HIGH Voltage (Note 17)	-975	-925	-875	-950	-890	-850	-925	-865	-825	mV
V <sub>OUTPP</sub>	Output Amplitude Voltage $-3.465~\text{V} \leq \text{V}_{\text{EE}} \leq -3.0~\text{V} \\ -3.0~\text{V} < \text{V}_{\text{EE}} \leq -2.375~\text{V}$	350 315	440 405	530 495	350 315	440 405	530 495	350 315	440 405	530 495	mV
V <sub>IH</sub>	Input HIGH Voltage (Single-Ended) (Notes 19 and 21)	V <sub>CC</sub> - 1435	V <sub>CC</sub> - 1000*	V <sub>CC</sub>	V <sub>CC</sub> - 1435	V <sub>CC</sub> - 1000*	V <sub>CC</sub>	V <sub>CC</sub> - 1435	V <sub>CC</sub> - 1000*	V <sub>CC</sub>	mV
V <sub>IL</sub>	Input LOW Voltage (Single-Ended) (Notes 20 and 21)	V <sub>IH</sub> - 2500	V <sub>CC</sub> - 1400*	V <sub>IH</sub> - 150	V <sub>IH</sub> - 2500	V <sub>CC</sub> - 1400*	V <sub>IH</sub> - 150	V <sub>IH</sub> - 2500	V <sub>CC</sub> - 1400*	V <sub>IH</sub> - 150	mV
V <sub>THR</sub>	Input Threshold Voltage (Single-Ended) (Note 21)	V <sub>EE</sub> + 1125		V <sub>CC</sub> - 75	V <sub>EE</sub> + 1125		V <sub>CC</sub> - 75	V <sub>EE</sub> + 1125		V <sub>CC</sub> - 75	mV
V <sub>IHCMR</sub>	Input HIGH Voltage Common Mode Range (Differential Configuration) (Note 18)	V <sub>EE</sub>	+ 1.2	0.0	V <sub>EE</sub> -	+ 1.2	0.0	V <sub>EE</sub>	+ 1.2	0.0	V
R <sub>TIN</sub>	Internal Input Termination Resistor	45	50	55	45	50	55	45	50	55	Ω
I <sub>IH</sub>	Input HIGH Current (@ V <sub>IH</sub> )		80	150		80	150		80	150	μΑ
I <sub>IL</sub>	Input LOW Current (@ V <sub>IL</sub> )		25	100		25	100		25	100	μΑ

<sup>\*</sup>Typicals used for testing purposes.

<sup>\*\*</sup>The device packaged in FCBGA-16 have maximum temperature specification of 70°C and devices packaged in QFN-16 have maximum temperature specification of 85°C.

<sup>16.</sup> Input and output parameters vary 1:1 with  $V_{CC}$ .

17. All outputs loaded with 50  $\Omega$  to  $V_{CC}$  –1.5 V for BGA package and  $V_{CC}$  – 2 V for QFN package.  $V_{OH}/V_{OL}$  measured at  $V_{IH}/V_{IL}$  (Typical).

<sup>18.</sup> V<sub>IHCMR</sub> min varies 1:1 with V<sub>EE</sub>, V<sub>IHCMR</sub> max varies 1:1 with V<sub>CC</sub>. The V<sub>IHCMR</sub> range is referenced to the most positive side of the differential input signal.

<sup>19.</sup> V<sub>IH</sub> cannot exceed V<sub>CC</sub>.  $|V_{IH} - V_{THR}| < 2600$  mV. 20. V<sub>IL</sub> always  $\geq V_{EE}$ .  $|V_{IL} - V_{THR}| < 2600$  mV. 21. V<sub>THR</sub> is the voltage applied to one input when running in single–ended mode.

#### Table 8. AC CHARACTERISTICS for FCBGA-16

 $V_{CC}$  = 0 V;  $V_{EE}$  = -3.465 V to -2.375 V or  $V_{CC}$  = 2.375 V to 3.465 V;  $V_{EE}$  = 0 V

		-	40°C		;	25°C		70°C			
Symbol	Characteristic	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
f <sub>max</sub>	Maximum Frequency (See Figure 4) (Note 22)	10.7	12		10.7	12		10.7	12		GHz
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation Delay to Output Differential	100	125	150	100	125	150	100	125	150	ps
t <sub>SKEW</sub>	Duty Cycle Skew (Note 23) Within-Device Skew (Note 24) Device-to-Device Skew (Note 25)		2 6 25	10 15 50		2 6 25	10 15 50		2 6 25	10 15 50	ps
<sup>†</sup> JITTER	$\begin{array}{ll} \text{RMS Random Clock Jitter} \\ \text{(Figure 4) (Note 27)} & f_{\text{in}} < 10 \text{ GHz} \\ \text{Peak-to-Peak Data Dependent Jitter} \\ \text{(Note 28)} & f_{\text{in}} < 10 \text{ Gb/s} \end{array}$		0.2	1		0.2 10	1		0.2	1	ps
V <sub>INPP</sub>	Input Voltage Swing/Sensitivity (Differential Configuration) (Note 26)	75		2600	75		2600	75		2600	mV
t <sub>r</sub>	Output Rise/Fall Times Q, Q (20% - 80%) @ 1 GHz	20	30	55	20	30	55	20	30	55	ps

<sup>22.</sup> Measured using a 500 mV source, 50% duty cycle clock source. All outputs loaded with 50  $\Omega$  to  $V_{CC}$  – 1.5 V. Input edge rates 40 ps

<sup>23.</sup> See Figure 6.  $t_{SKEW}$  =  $|t_{PLH} - t_{PHL}|$  for a nominal 50% Differential Clock Input Waveform.

<sup>24.</sup> Within-Device skew is measured between outputs under identical transitions and conditions on any one device.

<sup>25.</sup> Device-to-device skew for identical transitions at identical V<sub>CC</sub> levels.

<sup>26.</sup>  $V_{INPP}$  (MAX) cannot exceed  $V_{CC}$  –  $V_{EE}$  (applicable only when  $V_{CC}$ – $V_{EE}$  < 2600 mV). 27. Additive RMS Jitter with 50% duty cycle clock signal at 10 GHz.

<sup>28.</sup> Additive Peak-to-Peak data dependent jitter with NRZ PRBS 231-1 data at 10 Gb/s.

#### Table 9. AC CHARACTERISTICS for QFN-16

 $V_{CC}$  = 0 V;  $V_{EE}$  = -3.465 V to -2.375 V or  $V_{CC}$  = 2.375 V to 3.465 V;  $V_{EE}$  = 0 V

		_	-40°C		;	25°C		85°C			
Symbol	Characteristic	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
f <sub>max</sub>	Maximum Frequency (See Figure 4) (Note 29)	10.5	12		10.5	12		10.5	12		GHz
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation Delay to Output Differential	90	125	160	90	125	160	90	125	160	ps
t <sub>SKEW</sub>	Duty Cycle Skew (Note 30) Within-Device Skew (Note 31) Device-to-Device Skew (Note 32)		3 6 25	15 15 50		3 6 25	15 15 50		3 6 25	15 15 50	ps
<sup>†</sup> JITTER	RMS Random Clock Jitter (Figure 4) (Note 34) f <sub>in</sub> < 10 GHz Peak-to-Peak Data Dependent Jitter (Note 35) f <sub>in</sub> < 10 Gb/s		0.2	1		0.2 10	1		0.2	1	ps
V <sub>INPP</sub>	Input Voltage Swing/Sensitivity (Differential Configuration) (Note 33)	75		2600	75		2600	75		2600	mV
t <sub>r</sub>	Output Rise/Fall Times Q, Q (20% - 80%) @ 1 GHz	15	30	55	20	30	55	20	30	55	ps

<sup>29.</sup> Measured using a 500 mV source, 50% duty cycle clock source. All outputs loaded with 50  $\Omega$  to  $V_{CC}$  – 2.0 V. Input edge rates 40 ps

<sup>30.</sup> See Figure 6.  $t_{SKEW} = |t_{PLH} - t_{PHL}|$  for a nominal 50% Differential Clock Input Waveform.

<sup>31.</sup> Within-Device skew is measured between outputs under identical transitions and conditions on any one device.

<sup>32.</sup> Device-to-device skew for identical transitions at identical V<sub>CC</sub> levels.

<sup>33.</sup>  $V_{INPP}$  (MAX) cannot exceed  $V_{CC}$  –  $V_{EE}$  (applicable only when  $V_{CC}$ – $V_{EE}$  < 2600 mV). 34. Additive RMS Jitter with 50% duty cycle clock signal at 10 GHz.

<sup>35.</sup> Additive Peak-to-Peak data dependent jitter with NRZ PRBS 231-1 data at 10 Gb/s.

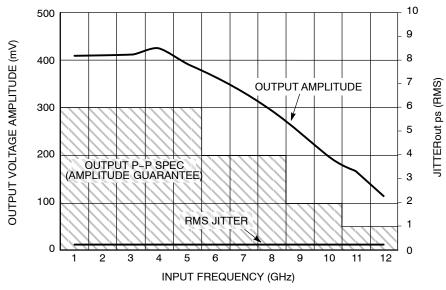
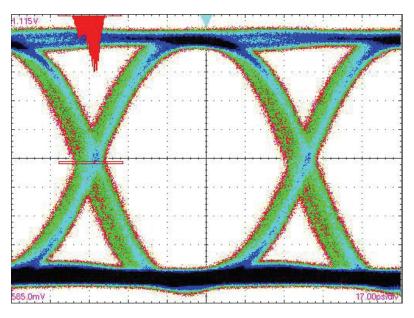


Figure 4. Output Voltage Amplitude ( $V_{OUTPP}$ ) / RMS Jitter vs. Input Frequency ( $f_{in}$ ) at Ambient Temperature (Typical)



X = 17 ps/DIV, Y = 53 mV/DIV

Figure 5. Eye Diagram at 10.8 Gbps (V<sub>CC</sub> – V<sub>EE</sub> = 3.3 V @ 25°C with Input Data Pattern of 2^31–1 PRBS. Total Pk–Pk System Jitter Including Signal Generator is 18 ps. This Data was taken by Acquiring 7000 Waveforms.)

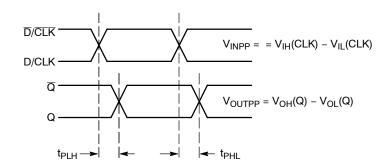


Figure 6. AC Reference Measurement

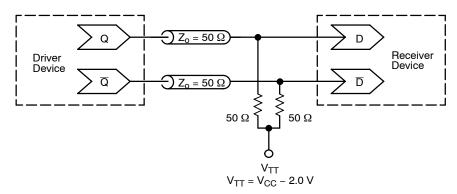


Figure 7. Typical Termination for Output Driver and Device Evaluation (See Application Note AND8020/D – Termination of ECL Logic Devices.)

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NBSG14BA	FCBGA-16	100 Units / Tray
NBSG14BAR2	FCBGA-16	500 / Tape & Reel
NBSG14MN	QFN-16	123 Units / Rail
NBSG14MNG	QFN-16 (Pb-Free)	123 Units / Rail
NBSG14MNR2	QFN-16	3000 / Tape & Reel
NBSG14MNR2G	QFN-16 (Pb-Free)	3000 / Tape & Reel

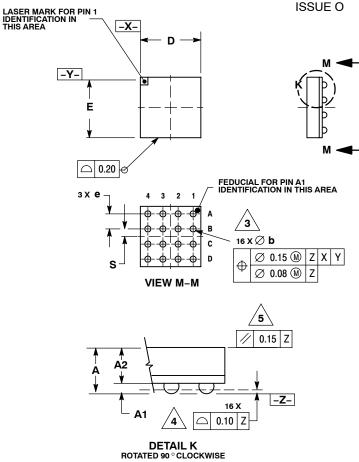
Board	Description
NBSG14BAEVB	NBSG14BA Evaluation Board

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### **PACKAGE DIMENSIONS**

#### FCBGA-16 **BA SUFFIX**

PLASTIC 4X4 (mm) BGA FLIP CHIP PACKAGE CASE 489-01

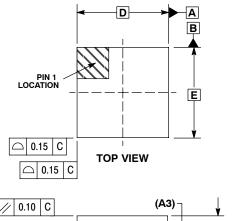


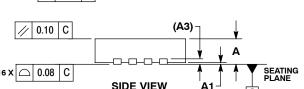
- NOTES:
  1. DIMENSIONS ARE IN MILLIMETERS.
  2. INTERPRET DIMENSIONS AND TOLERANCES
  PER ASME Y14.5M, 1994.
  3. DIMENSION b IS MEASURED AT THE MAXIMUM
  SOLDER BALL DIAMETER, PARALLEL TO DATUM
  PLANE Z.
  4. DATUM Z (SEATING PLANE) IS DEFINED BY THE
  SPHERICAL CROWNS OF THE SOLDER BALLS.
  5. PARALLELISM MEASUREMENT SHALL EXCLUDE
  ANY EFFECT OF MARK ON TOP SURFACE OF
  PACKAGE.

	MILLIMETERS							
DIM	MIN	MAX						
Α	1.40 MAX							
A1	0.25	0.35						
A2	1.20	REF						
b	0.30	0.50						
D	4.00	BSC						
Е	4.00	BSC						
е	1.00	BSC						
)	0.50	DOO						

#### PACKAGE DIMENSIONS

#### 16 PIN QFN CASE 485G-01 **ISSUE B**



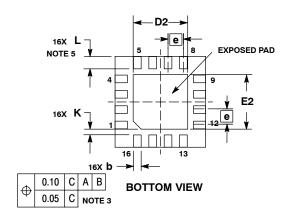


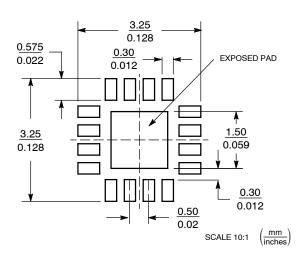
# 16 X \arr 0.08 \cdot C SIDE VIEW C

- DIMENSIONING AND TOLERANCING PER
- ASME Y14.5M, 1994.
  CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION 5 APPLIES TO PLATED
  TERMINAL AND IS MEASURED BETWEEN
  0.25 AND 0.30 MM FROM TERMINAL.
- COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.
- L<sub>max</sub> CONDITION CAN NOT VIOLATE 0.2 MM MINIMUM SPACING BETWEEN LEAD TIP

	MILLIMETERS	
DIM	MIN	MAX
Α	0.80	1.00
A1	0.00	0.05
АЗ	0.20 REF	
b	0.18	0.30
D	3.00 BSC	
D2	1.65	1.85
Е	3.00 BSC	
E2	1.65	1.85
е	0.50 BSC	
K	0.20	
L	0.30	0.50

#### **SOLDERING FOOTPRINT\***





\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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